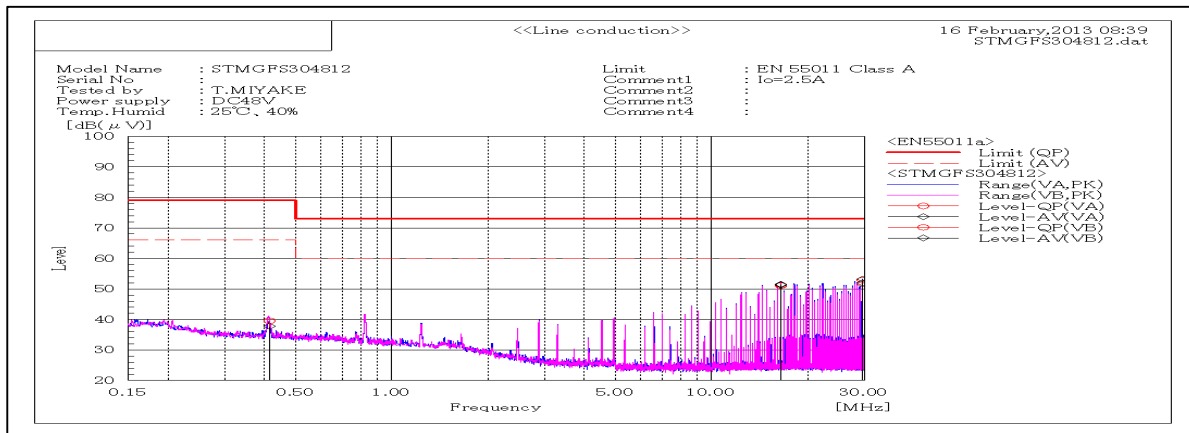
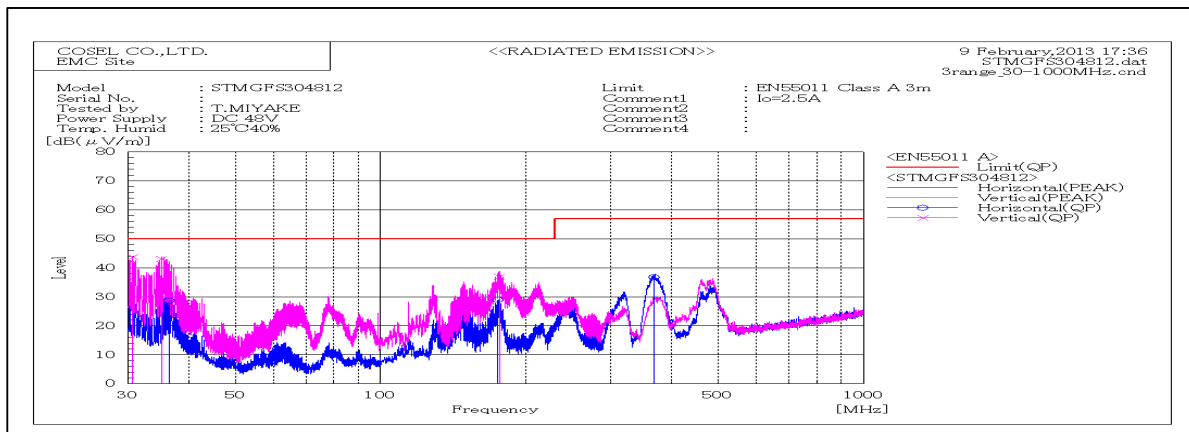


DATA SHEET		Date	18-Feb-13
Model	STMGFS304812	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	T.Miyake



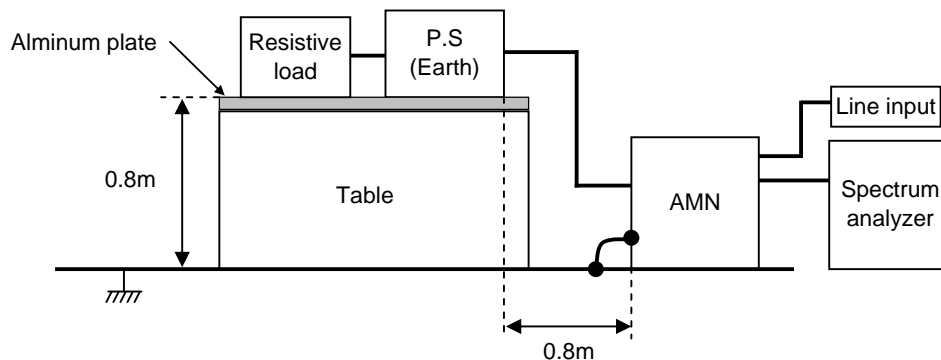
Frequency MHz	Harm	Line Phase	Reading dB(μV)		Factor dB	Level dB(μV)		Limit dB(μV)		Margin dB		Pass/ Fail	Remark
			QP	AV		QP	AV	QP	AV	QP	AV		
0.41459		VB	19.4	17.6	20.1	39.5	37.7	79	66	39.5	28.3	Pass	
16.49445		VB	30	30.3	21.1	51.1	51.4	73	60	21.9	8.6	Pass	
16.49305		VA	30.1	30.4	21.1	51.2	51.5	73	60	21.8	8.5	Pass	
29.68465		VB	30.9	31	20.9	51.8	51.9	73	60	21.2	8.1	Pass	
29.68165		VA	32.1	32.4	20.8	52.9	53.2	73	60	20.1	6.8	Pass	



Frequency MHz	Polarization	Stability	Reading dB(μV)		Space Loss dB	Level dB(mW)		Margin dB	Pass/Fail	Height cm	Angle deg	Remark
			QP	AV		QP	QP					
30.648	V	Stable	57.4	-13.6	43.8	50	6.2	Pass	101	231		
35.204	V	Stable	58	-14.9	43.1	50	6.9	Pass	100	0		
36.452	H	Stable	45.2	-16.5	28.7	50	21.3	Pass	155	62		
174.76	H	Stable	51.2	-22.2	29	50	21	Pass	155	227		
176.411	V	Stable	52.8	-16	36.8	50	13.2	Pass	101	285		
368.59	H	Stable	49.2	-12.4	36.8	57	20.2	Pass	103	273		

DATA SHEET		Date	18-Feb-13
Model	Circuit used for measurement	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	T.Miyake

## 1. Line conduction



## 2. Radiated emission

